INTEGRATED CIRCUIT TAG

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CLAIM
The ornamental design for an integrated circuit tag, as shown and described.

DESCRIPTION
FIG. 1 is a perspective view of an integrated circuit tag showing our new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a right side elevational view thereof;
FIG. 4 is a left side elevational view thereof;
FIG. 5 is a top plan view thereof; and
FIG. 6 is a bottom plan view thereof.
FIG. 7 is a reference front elevational view thereof;
FIG. 8 is a reference rear elevational view thereof;
FIG. 9 is a cross sectional view thereof cut along the line 9-9 of FIG. 7; and
FIG. 10 is a reference rear elevational view thereof showing the translucent portion in gray.
The broken lines shown in the drawings represent portions of the integrated circuit tag that form no part of the claimed design.

1 Claim, 5 Drawing Sheets
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**U.S. PATENT DOCUMENTS**

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